Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/574,698	OSAWA ET AL.	
Examiner	Art Unit	
THANH LAM	2834	

	SEARCHED				
Class	Subclass	Date	Examiner		
310	179,184, 233-234. 198.	11/23/2008	TL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
interference searched		11/23/2008	TL	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		